JOURNAL OF ELECTRONIC TESTING: Theory and Applications (JETTA)

Volume 34, Number 6, December 2018

Editorial
V.D. Agrawal 615


Test Technology Newsletter 621

QUANTUM-DOT CELLULAR AUTOMATA TESTING
Multiple Missing Cell Defect Modeling for QCA Devices
V.H. Dhare · U.S. Mehta 623

MIXED-SIGNAL TEST
Blind Calibration Method for Two-Channel Time-Interleaved Analog-to-Digital Converters Based on FFT
X. Bai · H. Hu · W. Li · F. Liu 643

APPROXIMATE COMPUTING
Generation Methodology for Good-Enough Approximate Modules of ATM
A.S. Hassan · T. Arifeen · H. Moradian · J.-A. Lee 651

BOOLEAN NETWORK THEORY
Path Representation in Circuit Netlists Using Linear-Sized ZDDs with Optimal Variable Ordering
S.N. Neophytou · M.K. Michael 667

LOW POWER SELF-TEST
LEEDS Recoding-Based Low Power Test-Compressive Architectures for Scan Designs
N. El Belghiti Alaoui · A. Boyer · P. Tounsi · A. Viard 685

PROTECTOR SECURITY
Near Lightwave Architectures for Secure FSM Design to Threat Fault Injection and Power Attacks
V.S. Rathee · G. Gao · S. Slama 697

Further articles can be found at link.springer.com

Instructions for Authors for J Electronic Test are available at www.springer.com/10836.